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PATENT

2876

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Allan Rosencwaig et al.

Application No.: 09/629,407

Filed: August 1, 2000

For: MEASUREMENT OF THIN FILMS
AND BARRIER LAYERS ON
PATTERNED WAFERS WITH
X-RAY REFLECTOMETRY

Group No.: 2876

Examiner: H.K. Song

ASSOCIATE POWER OF ATTORNEY

121 Spear Street, Suite 290
San Francisco, CA 94105

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Georgia K. Stich

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Sir:

Please recognize as Associate Patent Attorney in this case:

Name of Attorney: Brian J. Keating

Address: 121 Spear Street, Suite 290
San Francisco, CA 94111

Reg. No.: 39,520

Telephone: (415) 512-1312

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Date: February 18, 2003

By:

Kathleen A. Frost
Kathleen A. Frost (Reg. No. 37,326)

Attorneys for Applicant(s)

121 Spear Street, Suite 290
San Francisco, CA 94105
Tel.: (415) 512-1312
Fax: (415) 512-1362

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